MOSFET - Symmetrical **Dual N-Channel** 40 V, 4.5 mΩ, 60 A

NTTFD4D0N04HL

General Description

This device includes two specialized N-Channel MOSFETs in a dual package. The switch node has been internally connected to enable easy placement and routing of synchronous buck converters. The control MOSFET (Q2) and synchronous (Q1) have been designed to provide optimal power efficiency.

Features

Q1: N-Channel

- Max $r_{DS(on)} = 4.5 \text{ m}\Omega$ at $V_{GS} = 10 \text{ V}$, $I_D = 10 \text{ A}$
- Max $r_{DS(on)} = 7 \text{ m}\Omega$ at $V_{GS} = 4.5$, $I_D = 8.0 \text{ A}$

Q2: N-Channel

- Max $r_{DS(on)} = 4.5 \text{ m}\Omega$ at $V_{GS} = 10 \text{ V}$, $I_D = 10 \text{ A}$
- Max $r_{DS(on)} = 7 \text{ m}\Omega$ at $V_{GS} = 4.5$, $I_D = 8.0 \text{ A}$
- Low Inductance Packaging Shortens Rise/Fall Times, Resulting in Lower Switching Losses
- RoHS Compliant

Typical Applications

- Computing
- Communications
- General Purpose Point of Load

PIN DESCRIPTION

Pin	Name	Description
1, 11, 12	GND (LSS)	Low Side Source
2	LSG	Low Side Gate
3, 4, 5, 6	V + (HSD)	High Side Drain
7	HSG	High Side Gate
8, 9, 10	SW	Switching Node, Low Side Drain

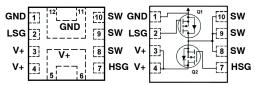


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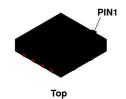
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V _{(BR)DSS}	R _{DS(ON)} MAX	I _D MAX
40.1/	4.5 mΩ @ 10 V	60 A
40 V	7 mΩ @ 4.5 V	60 A

ELECTRICAL CONNECTION



Dual N-Channel MOSFET





Bottom

WQFN12, 3x3 CASE 510CJ

MARKING DIAGRAM

O D4D0 AYWWZZ

D4D0 = Specific Device Code
A = Assembly Plant Code
Y = Numeric Year Code
WW = Work Week Code
ZZ = Assembly Lot Code

ORDERING INFORMATION

Device	Package	Shipping†
NTTFD4D0N04HLTWG	WQFN12 (Pb-Free)	3000 / Tape & Reel

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

MOSFET MAXIMUM RATINGS ($T_A = 25^{\circ}C$, Unless otherwise specified)

Symbol	Par	ameter		Q1	Q2	Units
V _{DS}	Drain-to-Source Voltage			40	40	V
V _{GS}	Gate-to-Source Voltage			±20	±20	V
I _D	Drain Current -Continuous	T _C = 25°C	(Note 4)	60	60	Α
	-Continuous	T _C = 100°C	(Note 4)	37	37	
	-Continuous	T _A = 25°C		15 (Note 1a)	15 (Note 1b)	
	-Pulsed	T _A = 25°C		349	349	
E _{AS}	Single Pulse Avalanche Energy		(Note 3)	67	67	mJ
P_{D}	Power Dissipation for Single Operation	$T_C = 25^{\circ}C$		26	26	W
	Power Dissipation for Single Operation	$T_A = 25^{\circ}C$		1.7 (Note 1a)	1.7 (Note 1b)	
T _J , T _{STG}	Operating and Storage Junction Temp	erature Range		–55 to	+150	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

THERMAL CHARACTERISTICS

Symbol	Parameter	Q1	Q2	Units
$R_{ heta JC}$	Thermal Resistance, Junction-to-Case	4.8	4.8	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (Note 1a), max copper	70 (Note 1a)	70 (Note 1b)	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (Note 1c), min copper	135 (Note 1a)	135 (Note 1b)	

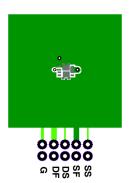
ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise noted)

Symbol	Parameter	Test Conditions	Туре	Min	Тур	Max	Units	
OFF CHARACTERISTICS								
BV _{DSS}	Drain-to-Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	Q1	40			V	
		$I_D = 250 \mu A, V_{GS} = 0 V$	Q2	40			1	
ΔBV_{DSS}	Breakdown Voltage Temperature	I _D = 250 μA, referenced to 25°C	Q1		16.63		mV/°C	
ΔT_{J}	Coefficient	I _D = 250 μA, referenced to 25°C	Q2		16.63		1	
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 40 V, V _{GS} = 0 V	Q1			10	μΑ	
		V _{DS} = 40 V, V _{GS} = 0 V	Q2			10	1	
I _{GSS}	Gate-to-Source Leakage Current,	$V_{GS} = +20/-16 \text{ V}, V_{DS} = 0 \text{ V}$	Q1			±100	nA	
	Forward	V _{GS} = +20/-16 V, V _{DS} = 0 V	Q2			±100	1	
ON CHAR	ACTERISTICS							
V _{GS(th)}	Gate-to-Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 50 \mu A$	Q1	1.2	1.5	2.0	V	
		$V_{GS} = V_{DS}$, $I_D = 50 \mu A$	Q2	1.2	1.5	2.0	1	
$\Delta V_{GS(th)}$	Gate-to-Source Threshold Voltage	$I_D = 50 \mu A$, referenced to $25^{\circ}C$	Q1		-5.75		mV/°C	
ΔT_{J}	Temperature Coefficient	I _D = 50 μA, referenced to 25°C	Q2		-5.75		1	
r _{DS(on)}	Drain-to-Source On Resistance	V _{GS} = 10 V, I _D = 10 A	Q1		3.7	4.5	mΩ	
		V _{GS} = 4.5 V, I _D = 8 A			5.8	7	1	
		V _{GS} = 10 V, I _D = 10 A, T _J = 125°C			6.4		1	
r _{DS(on)}	Drain-to-Source On Resistance	V _{GS} = 10 V, I _D = 10 A	Q2		3.7	4.5	mΩ	
		V _{GS} = 4.5 V, I _D = 8 A			5.8	7	1	
		$V_{GS} = 10 \text{ V}, I_D = 10 \text{ A}, T_J = 125^{\circ}\text{C}$			6.4		1	
9FS	Forward Transconductance	V _{DS} = 15 V, I _D = 10 A	Q1		61		S	
		V _{DS} = 15 V, I _D = 10 A	Q2		61		1	

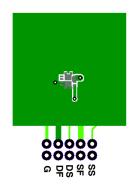
ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise noted)

Symbol	Parameter	Test Conditions	Type	Min	Тур	Max	Units
OYNAMIC	CHARACTERISTICS		•				.4
C _{ISS}	Input Capacitance	Q1:	Q1		1100		pF
		$V_{DS} = 20 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ Mhz}$	Q2		1100		1
C _{OSS}	Output Capacitance	Q2:	Q1		271		pF
		V _{DS} = 20 V, V _{GS} = 0 V, f = 1 MHz	Q2		271		1
C _{RSS}	Reverse Transfer Capacitance		Q1		22		pF
			Q2		22		1
R_{G}	Gate Resistance	T _A = 25°C	Q1		2.0		Ω
			Q2		2.0		
WITCHIN	IG CHARACTERISTICS						
td _(ON)	Turn-On Delay Time	Q1:	Q1		9.5		ns
		V_{DD} = 32 V, I_{D} = 30.5 A, V_{GS} = 4.5 V, R_{GEN} = 2.5 Ω	Q2		9.5		1
t _r	Rise Time	Q2:	Q1		5.6		ns
		$V_{DD} = 32 \text{ V}, I_D = 30.5 \text{ A},$	Q2		5.6		1
t _{D(OFF)}	Turn-Off Delay Time	$V_{GS} = 4.5 \text{ V}, R_{GEN} = 2.5 \Omega$	Q1		1.7		ns
			Q2		1.7		
t _f	Fall Time		Q1		5.8		ns
			Q2		5.8		1
Qg	Total Gate Charge	V _{GS} = 0 V to 10 V	Q1		18		nC
			Q2		18		1
Qg	Total Gate Charge	V _{GS} = 0 V to 4.5 V	Q1		8.6		nC
		01.	Q2		8.6		
Q_{gs}	Gate-to-Source Gate Charge	- Q1: V _{DD} = 32 V,	Q1		3.1		nC
		I _D = 30.5 A Q2:	Q2		3.1		
Q_{gd}	Gate-to-Drain "Miller" Charge	$V_{DD} = 32 \text{ V},$	Q1		3.2		nC
		I _D = 30.5 A	Q2		3.2		
RAIN-SO	DURCE DIODE CHARACTERISTICS						
V_{SD}	Source to Drain Diode Forward Voltage	V _{GS} = 0 V, I _S = 10 A (Note 2)	Q1		0.78	1.2	V
		V _{GS} = 0 V, I _S = 10 A (Note 2)	Q2		0.78	1.2	
t _{rr}	Reverse Recovery Time	Q1:	Q1		26		ns
		I _F = 30.5 A, di/dt = 100 A/μs Q2:	Q2		26		
Q _{rr}	Reverse Recovery Charge	I _F = 30.5 A, di/dt = 100 A/μs	Q1		9		nC
			Q2		9		1

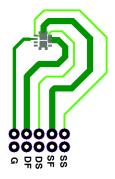
Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.
 R_{θJA} is determined with the device mounted on a 1 in² pad 2 oz copper pad on a 1.5 × 1.5 in. board of FR-4 material. R_{θCA} is determined by the user's board design.



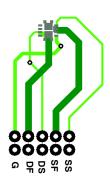
a) 70°C/W when mounted on a 1 in² pad of 2 oz copper.



b) 70°C/W when mounted on a 1 in² pad of 2 oz copper.



c) 135°C/W when mounted on a minimum pad of 2 oz copper.



d) 135°C/W when mounted on a minimum pad of 2 oz copper.

- 2. Pulse Test: Pulse Width < 300 $\mu s,$ Duty cycle < 2.0%.
- Q1: E_{AS} of 67 mJ is based on starting T_J = 25°C; N-ch: L = 1 mH, I_{AS} = 11.6 A, V_{DD} = 40 V, V_{GS} = 10 V. 100% test at L = 1 mH, I_{AS} = 11.6 A. Q2: E_{AS} of 67 mJ is based on starting T_J = 25°C; N-ch: L = 1 mH, I_{AS} = 11.6 A, V_{DD} = 40 V, V_{GS} = 10 V. 100% test at L = 1 mH, I_{AS} = 11.6 A.
 Computed continuous current limited to Max Junction Temperature only, actual continuous current will be limited by thermal
- & electro-mechanical application board design.

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TYPICAL CHARACTERISTICS

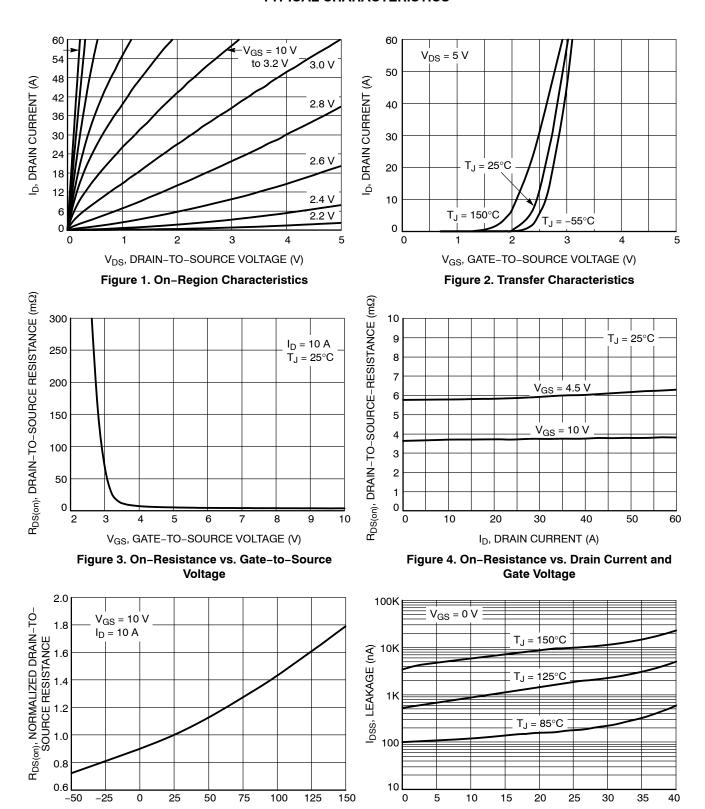


Figure 5. On–Resistance Variation with Temperature

T_J, JUNCTION TEMPERATURE (°C)

Figure 6. Drain-to-Source Leakage Current vs. Voltage

V_{DS}, DRAIN-TO-SOURCE VOLTAGE (V)

TYPICAL CHARACTERISTICS

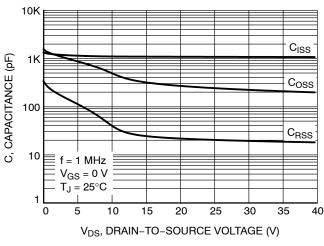


Figure 7. Capacitance Variation

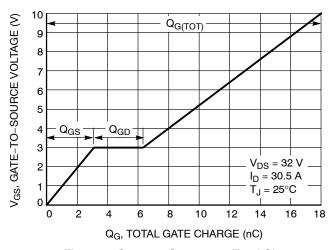


Figure 8. Gate-to-Source vs. Total Charge

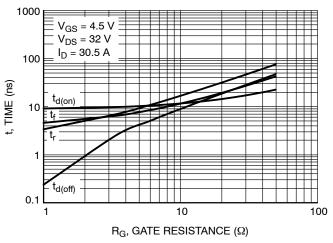


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

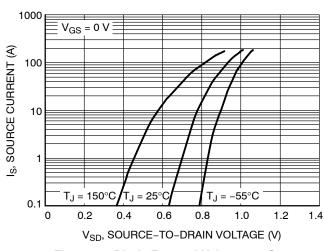


Figure 10. Diode Forward Voltage vs. Current

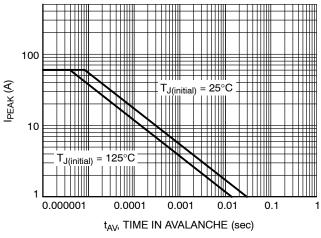


Figure 11. Unclamped Inductive Switching Capability

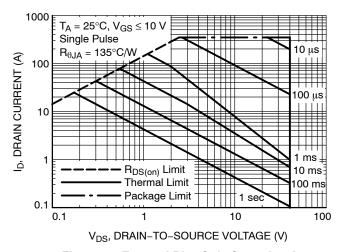


Figure 12. Forward Bias Safe Operating Area

TYPICAL CHARACTERISTICS

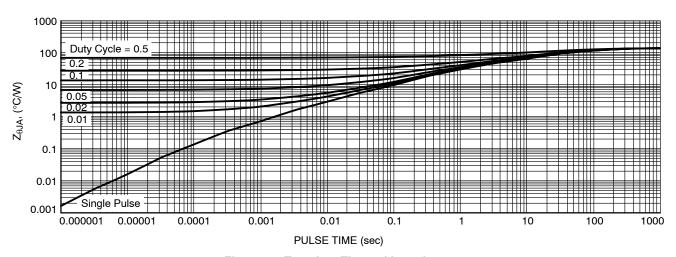


Figure 13. Transient Thermal Impedance

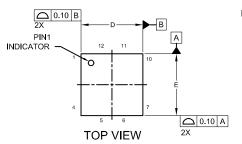




WQFN12 3.3X3.3, 0.65P

CASE 510CJ ISSUE A

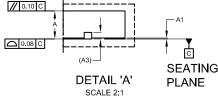
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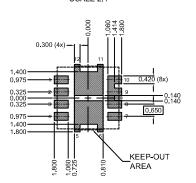


NOTES:

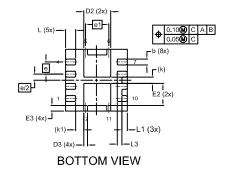
- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 2009.
- 2. CONTROLLING DIMENSION: MILLIMETERS
- 3. COPLANARITY APPLIES TO THE EXPOSED
- 4. SEATING PLANE IS DEFINED BY THE TERMINALS. "A1" IS DEFINED AS THE DISTANCE FROM THE SEATING PLANE TO THE LOWEST POINT ON THE PACKAGE BODY.
- 5. IT IS RECOMMENDED TO HAVE NO TRACES OR VIAS WITHIN THE KEEP OUT AREA.







MILLIMETERS DIM MIN NOM MAX 0.70 0.75 08.0 Α 0.00 Α1 0.05 А3 0.20 REF 0.27 0.32 0.37 b D 3.20 3.30 3.40 D2 1.54 1.34 1.44 D3 0.10 0.20 0.30 Ε 3.20 3.30 3.40 E2 1.09 1.19 1.29 E3 0.20 0.30 0.40 0.65 BSC е e/2 0.325 BSC 1.24 BSC e1 k 0.33 REF k1 0.43 REF L 0.44 0.54 0.64 0.19 L1 0.29 0.39 L3 0.15 0.25 0.35



GENERIC MARKING DIAGRAM*



XXXX = Specific Device Code

A = Assembly Location

Y = Year WW = Work Week

= Pb-Free Package

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "•", may or may not be present. Some products may not follow the Generic Marking.

LAND PATTERN
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